

Notic of R ferences Cited	Application/Control No. 09/690,271	Applicant(s)/Patent Under Reexamination CHANG, SE-LEE ET AL	
	Examiner Susan W Berman	Art Unit 1711	Page 1 of 1

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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